

### NDS356P

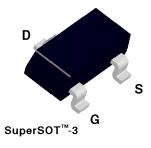
# P-Channel Logic Level Enhancement Mode Field Effect Transistor

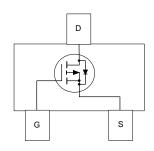
### **General Description**

These P-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management, portable electronics, and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

#### **Features**

- $\qquad \text{-1.1 A, -20V. } \mathsf{R}_{\mathsf{DS}(\mathsf{ON})} = 0.3 \Omega \ @ \mathsf{V}_{\mathsf{GS}} = \text{-4.5V.}$
- Proprietary package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Exceptional on-resistance and maximum DC current capability.
- Compact industry standard SOT-23 surface mount package.





## Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		NDS356P	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage - Continuous		± 12	V
I <sub>D</sub>	Maximum Drain Current - Continuous	(Note 1a)	±1.1	Α
	- Pulsed		±10	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		250	°C/W
Anv		(Note 1a)		
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS	·					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$				-5	μΑ
			T <sub>J</sub> =125°C			-20	μΑ
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 12 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAF	RACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$		-0.8	-1.6	-2.5	V
			T <sub>J</sub> =125°C	-0.5	-1.3	-2.2	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{D} = -1.1 \text{ A}$				0.3	Ω
			T <sub>J</sub> =125°C			0.4	
		$V_{GS} = -10 \text{ V}, I_{D} = -1.3 \text{ A}$				0.21	
I <sub>D(ON)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$		-3			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -1.1 \text{ A}$			1.8		S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$			180		pF
C <sub>oss</sub>	Output Capacitance				255		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				60		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t <sub>d(on)</sub>	Turn - On Delay Time	$V_{DD} = -10 \text{ V}, \ I_{D} = -1 \text{ A},$ $V_{GS} = -10 \text{ V}, \ R_{GEN} = 50 \Omega$			7	15	ns
t <sub>r</sub>	Turn - On Rise Time				17	30	ns
$t_{d(off)}$	Turn - Off Delay Time				56	90	ns
t <sub>f</sub>	Turn - Off Fall Time				41	80	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -1.1 \text{ A}, V_{GS} = -5 \text{ V}$			3.5	5	nC
$Q_{gs}$	Gate-Source Charge					1.5	nC
$Q_{gd}$	Gate-Drain Charge					2	nC

Electrical Characteristics (T <sub>A</sub> = 25°C unless otherwise noted)							
Symbol	Parameter	Conditions	Min	Min Typ M		Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
Is	Maximum Continuous Drain-Source Diode Forward Current				-0.6	Α	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-4	Α	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -1.1 A (Note 2)		-0.85	-1.2	V	

#### Notes:

1. R<sub>gut</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>gut</sub> is guaranteed by design while R<sub>gut</sub> is determined by the user's board design.

$$P_D(t) = \frac{T_{J} - T_A}{R_{\theta J} A(t)} = \frac{T_{J} - T_A}{R_{\theta J} d^{\dagger} R_{\theta C} A(t)} = I_D^2(t) \times R_{DS(ON)} e_{T_J}$$

Typical  $R_{_{\theta^{J\!A}}}$  using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 250°C/W when mounted on a 0.02 in² pad of 2oz cpper.

b. 270°C/W when mounted on a 0.001 in  $^{\!2}$  pad of 2oz cpper.





Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

## **Typical Electrical Characteristics**

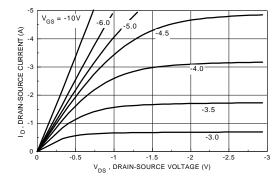


Figure 1. On-Region Characteristics

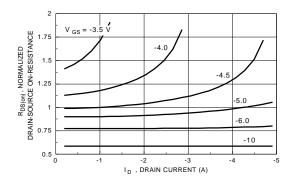


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

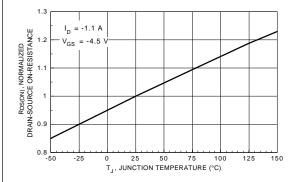


Figure 3. On-Resistance Variation with Temperature

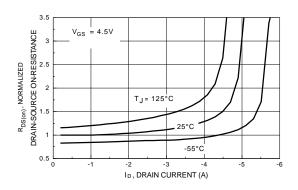


Figure 4. On-Resistance Variation with Drain Current and Temperature

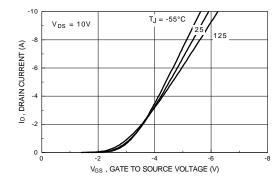


Figure 5. Transfer Characteristics

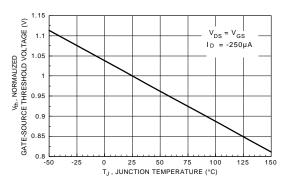


Figure 6. Gate Threshold Variation with Temperature

## Typical Electrical Characteristics (continued)

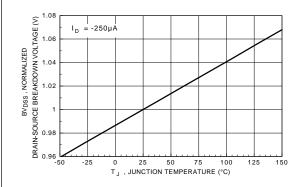


Figure 7. Breakdown Voltage Variation with Temperature

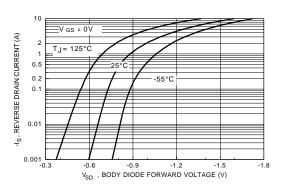


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature

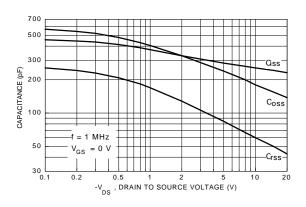


Figure 9. Capacitance Characteristics

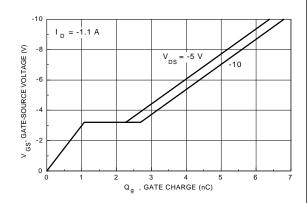


Figure 10. Gate Charge Characteristics

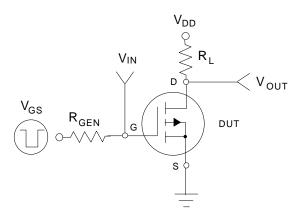


Figure 11. Switching Test Circuit

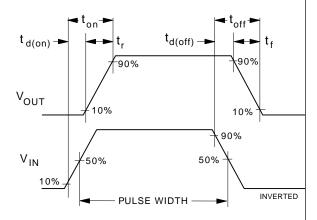
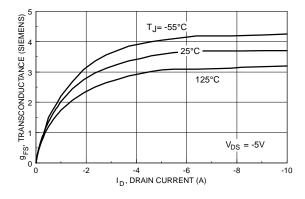


Figure 12. Switching Waveforms

### **Typical Electrical Characteristics (continued)**



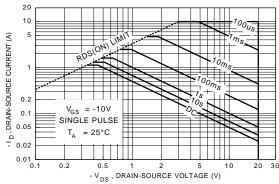


Figure 13. Transconductance Variation with Drain Current and Temperature

Figure 14. Maximum Safe Operating Area

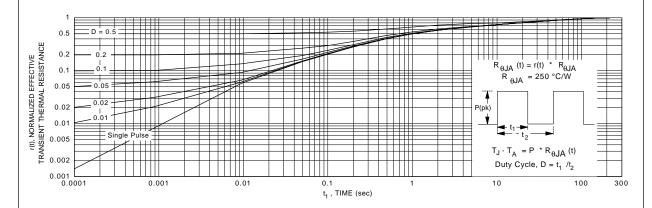


Figure 15. Transient Thermal Response Curve

Note: Characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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